

Notice of References Cited	Application/Control No. 10/779,779	Applicant(s)/Patent Under Reexamination NIIYA, HIROTAKA	
	Examiner Wen-Ying P. Chen	Art Unit 2871	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0113927	08-2002	Ha et al.	349/113
*	B	US-2003/0076464	04-2003	Ozawa et al.	349/113
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
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FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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